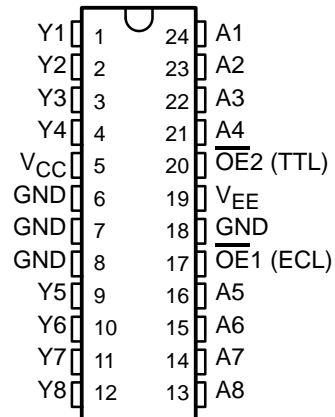


- 100K Compatible
- Open-Collector Outputs Drive Bus Lines or Buffer Memory Address Registers
- ECL and TTL Control Inputs
- Flow-Through Architecture Optimizes PCB Layout
- Center-Pin V_{CC} , V_{EE} , and GND Configurations Minimize High-Speed Switching Noise
- Package Options Include “Small Outline” Packages and Standard Plastic 300-mil DIPs

IR NT PACKAGE

(TOP VIEW)



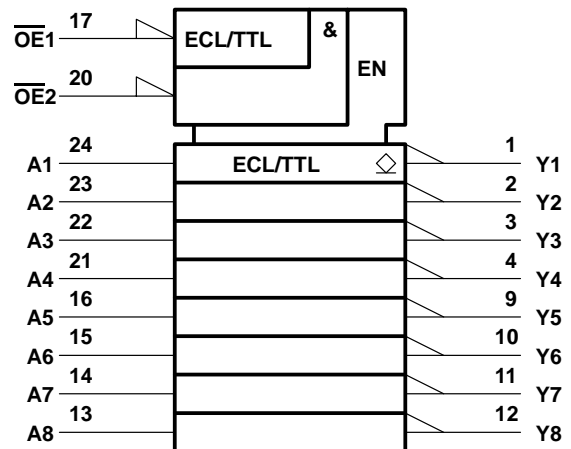
description

This octal ECL-to-TTL translator is designed to provide efficient translation between a 100K signal environment and a TTL signal environment. This device is designed specifically to improve the performance and density of ECL-to-TTL CPU/bus oriented functions such as memory address drivers, clock drivers, and bus-oriented receivers and transmitters while eliminating the need for three-state overlap protection.

Two output enables, $\overline{OE}1$ and $\overline{OE}2$, are provided. These enable inputs are ANDed together with $\overline{OE}1$ being ECL-compatible and $\overline{OE}2$ being TTL-compatible. This offers the choice of controlling the outputs of the device from either a TTL or ECL signal environment.

The SN100KT5538 is characterized for operation from 0°C to 85°C.

logic symbol†



† This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

FUNCTION TABLE

| OUTPUT ENABLE | | DATA INPUT A | OUTPUT (TTL) Y |
|------------------|------------------|-----------------|-------------------|
| $\overline{OE}1$ | $\overline{OE}2$ | | |
| H | X | X | H |
| X | H | X | H |
| L | L | L | H |
| L | L | H | L |

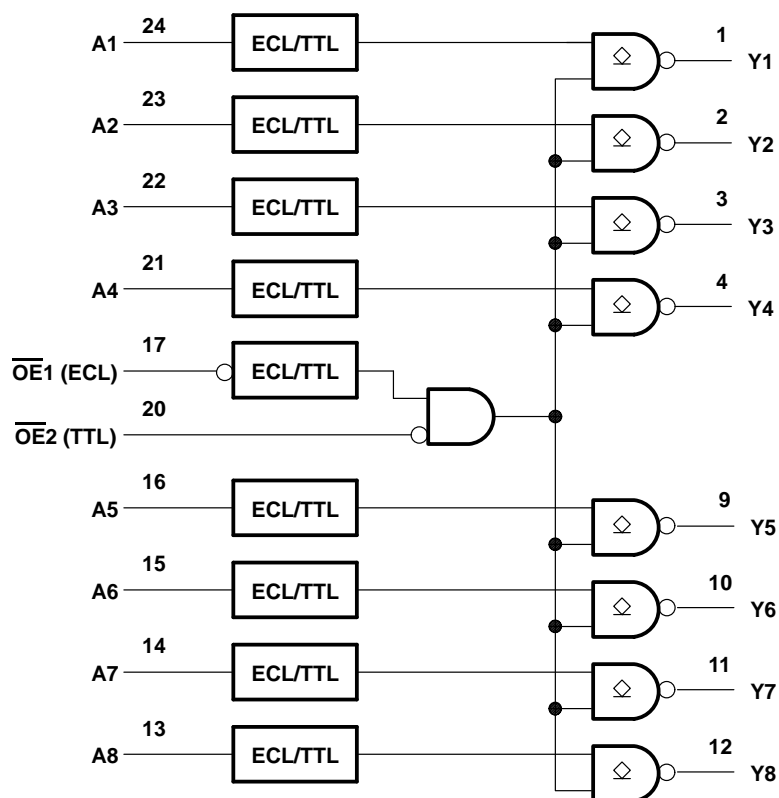
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OCTAL ECL-TO-TTL TRANSLATOR

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logic diagram (positive logic)



absolute maximum ratings over operating free-air temperature range (unless otherwise noted)[†]

| | |
|---|--------------------|
| Supply voltage range, V_{CC} | –0.5 V to 7 V |
| Supply voltage range, V_{EE} | –8 V to 0 V |
| Input voltage range (TTL) (see Note 1) | –1.2 V to 7 V |
| Input voltage range (ECL) | V_{EE} to 0 V |
| Input current range (TTL) | –30 mA to 5 mA |
| Current into any output in the low state | 96 mA |
| Voltage applied to any output in the high state | –0.5 V to V_{CC} |
| Operating temperature range | 0°C to 85°C |
| Storage temperature range | –65°C to 150°C |

[†] Stresses beyond those listed under “absolute maximum ratings” may cause permanent damage to the device. These are stress ratings only and functional operation of the device at these or any other conditions beyond those indicated under “recommended operating conditions” is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTE 1: The TTL input voltage ratings may be exceeded provided the input current ratings are observed.

recommended operating conditions

| | | MIN | NOM | MAX | UNIT |
|-----------------|--------------------------------|------------------|------|-------|------|
| V _{CC} | TTL supply voltage | 4.5 | 5 | 5.5 | V |
| V _{EE} | ECL supply voltage | –4.2 | –4.5 | –4.8 | V |
| V _{IH} | High-level input voltage | TTL | | 2 | V |
| | | ECL (see Note 2) | | –1150 | mV |
| V _{IL} | Low-level input voltage | TTL | | 0.8 | V |
| | | ECL (see Note 2) | | –1810 | mV |
| V _{OH} | TTL high-level output voltage | | | 5.5 | V |
| I _{OL} | TTL low-level output current | | | 48 | mA |
| I _{IK} | TTL input clamp current | | | –18 | mA |
| T _A | Operating free-air temperature | 0 | | 85 | °C |

NOTE 2: The algebraic convention, in which the least positive (most negative) value is designated minimum, is used in this data sheet for logic levels only.

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

| PARAMETER | TEST CONDITIONS | MIN | TYP† | MAX | UNIT |
|------------------|--|------|------|------|------|
| V _{IK} | OE2 only V _{CC} = 4.5 V, V _{EE} = –4.2 V, I _I = –18 mA | | | –1.2 | V |
| V _{OL} | V _{CC} = 4.5 V, V _{EE} = –4.5 V ± 0.3 V, I _{OL} = 48 mA | 0.38 | 0.55 | | V |
| I _I | OE2 only V _{CC} = 5.5 V, V _{EE} = –4.8 V, V _I = 7 V | | | 0.1 | mA |
| I _{IH} | OE2 only V _{CC} = 5.5 V, V _{EE} = –4.8 V, V _I = 2.7 V | | | 20 | |
| | A inputs and OE1 V _{CC} = 5.5 V, V _{EE} = –4.8 V, V _I = –840 mV | | | 350 | μA |
| I _{IL} | OE2 only V _{CC} = 5.5 V, V _{EE} = –4.8 V, V _I = 0.5 V | | | –0.5 | mA |
| | A inputs and OE1 V _{CC} = 5.5 V, V _{EE} = –4.8 V, V _I = –1810 mV | 0.5 | | | μA |
| I _{OH} | V _{CC} = 4.5 V, V _{EE} = –4.2 V, V _{OH} = 5.5 V | | | 250 | μA |
| I _{CCH} | V _{CC} = 5.5 V, V _{EE} = –4.8 V | | 66 | 95 | mA |
| I _{CCL} | V _{CC} = 5.5 V, V _{EE} = –4.8 V | | 79.5 | 114 | mA |
| I _{EE} | V _{CC} = 5.5 V, V _{EE} = –4.2 V | | –23 | –33 | mA |
| C _i | V _{CC} = 5.5 V, V _{EE} = –4.5 V | | 5 | | pF |
| C _o | V _{CC} = 5.5 V, V _{EE} = –4.5 V | | 5 | | pF |

switching characteristics over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted) (see Figure 1)

| PARAMETER | FROM (INPUT) | TO (OUTPUT) | C _L = 50 pF, R ₁ = 500 Ω, R ₂ = 500 Ω | | | UNIT |
|------------------|-------------------------------|----------------|--|------|------|------|
| | | | MIN | TYP† | MAX | |
| t _{PLH} | Any A | Y | 6.4 | 9.1 | 11.7 | ns |
| t _{PHL} | | | 2.7 | 4.9 | 7.2 | |
| t _{PLH} | $\overline{\text{OE}}1$ (ECL) | Y | 7 | 10.1 | 13.3 | ns |
| t _{PHL} | | | 3.6 | 6.2 | 8.8 | |
| t _{PLH} | $\overline{\text{OE}}2$ (TTL) | Y | 6.5 | 9.1 | 11.6 | ns |
| t _{PHL} | | | 2.8 | 5.3 | 7.9 | |

† All typical values are at V_{CC} = 5 V, V_{EE} = –4.5 V, T_A = 25°C.

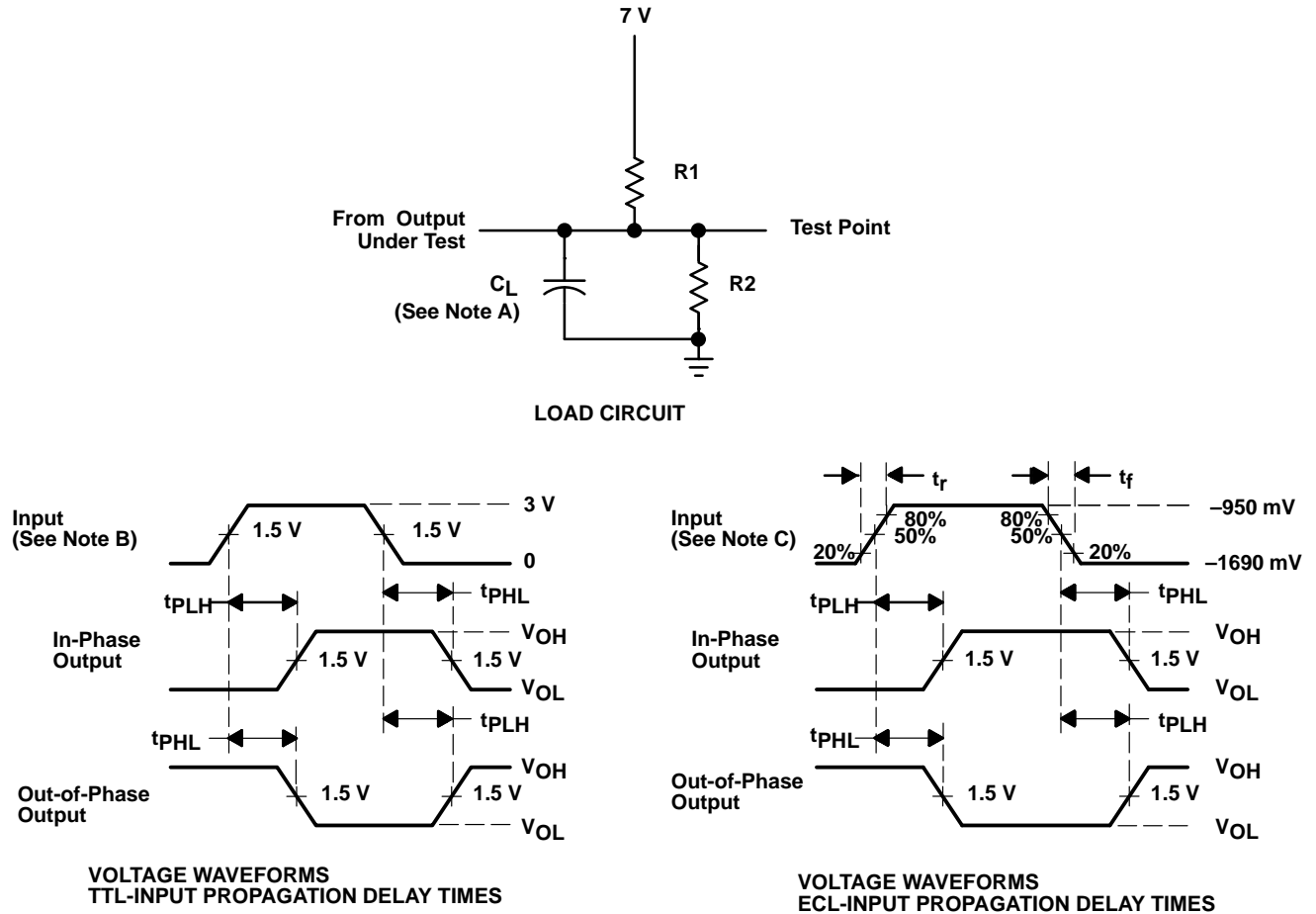
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OCTAL ECL-TO-TTL TRANSLATOR

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PARAMETER MEASUREMENT INFORMATION



- NOTES:
- A. C_L includes probe and jig capacitance.
 - B. For TTL inputs, input pulses are supplied by generators having the following characteristics: $PRR \leq 10$ MHz, $Z_O = 50 \Omega$, $t_r \leq 2.5$ ns, $t_f \leq 2.5$ ns.
 - C. For ECL inputs, input pulses are supplied by generators having the following characteristics: $PRR \leq 10$ MHz, $Z_O = 50 \Omega$, $t_r \leq 0.7$ ns, $t_f \leq 0.7$ ns.
 - D. The outputs are measured one at a time with one transition per measurement.

Figure 1. Load Circuit and Voltage Waveforms

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